


<b>Search Notes</b> 	<b>Application/Control No.</b> 10524715	<b>Applicant(s)/Patent Under Reexamination</b> LEE ET AL.
	<b>Examiner</b> Nguyen, Hai V	<b>Art Unit</b> 2618

SEARCHED			
Class	Subclass	Date	Examiner
725	32	01/23/2008	HN
455	3.01	02/06/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	02/05/2008	HN
EAST search updated (see search history printout report)	12/15/2008	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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